HEARING AID COMPATIBILITY

Applicant Name:
Samsung Electronics, Co. Ltd.
18600 Broadwick St.
Rancho Dominguez, CA 90220
United States

Date of Testing:
1/26/2012
Test Site/Location:
PCTEST Lab, Columbia, MD, USA
Test Report Serial No.:
0Y1201230120.A3L

FCC ID: **A3LSPHL700**

APPLICANT: **SAMSUNG ELECTRONICS, CO. LTD.**

Scope of Test: Audio Band Magnetic Testing (T-Coil)
Application Type: Certification
FCC Rule Part(s): CFR § 20.19(b)
HAC Standard: ANSI C63.19-2007 §6.3(v), §7.3(v)
EUT Type: Portable Handset
Model(s): SPH-L700
Test Device Serial No.: *Pre-Production Sample* [S/N: HAC T]

Band & Mode	Tx Frequency	C63.19-2007 HAC Category:
Cell. CDMA/EVDO - FCC Rule Part 22H	824.70 - 848.31 MHz	**T3 (SIGNAL TO NOISE CATEGORY)**
Cell. CDMA/EVDO - FCC Rule Part 90S	817.90 - 823.10 MHz	
PCS CDMA/EVDO - FCC Rule Part 24E	1851.25 - 1908.75 MHz	
LTE Band 25 (PCS) - FCC Rule Part 24E	1852.5 - 1912.5 MHz	
2.4 GHz WLAN - FCC Rule Part 15C	2412 - 2462 MHz	
5.8 GHz WLAN - FCC Rule Part 15C	5745 - 5825 MHz	
5.2 GHz WLAN - FCC Rule Part 15E	5180 - 5240 MHz	
5.3 GHz WLAN - FCC Rule Part 15E	5260 - 5320 MHz	
5.5 GHz WLAN - FCC Rule Part 15E	5500 - 5700 MHz	
Bluetooth - FCC Rule Part 15C	2402 - 2480 MHz	

This wireless portable device has been shown to be hearing-aid compatible under the above rated category, specified in ANSI/IEEE Std. C63.19-2007 and had been tested in accordance with the specified measurement procedures. Hearing-Aid Compatibility is based on the assumption that all production units will be designed electrically identical to the device tested in this report. Test results reported herein relate only to the item(s) tested. For North American bands only.

I attest to the accuracy of data. All measurements reported herein were performed by me or were made under my supervision and are correct to the best of my knowledge and belief. I assume full responsibility for the completeness of these measurements and vouch for the qualifications of all persons taking them.

Randy Ortanez
President

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1. INTRODUCTION

On July 10, 2003, the Federal Communications Commission (FCC) adopted new rules requiring wireless manufacturers and service providers to provide digital wireless phones that are compatible with hearing aids. The FCC has modified the exemption for wireless phones under the Hearing Aid Compatibility Act of 1998 (HAC Act) in WT Docket 01-309 RM-8658[1] to extend the benefits of wireless telecommunications to individuals with hearing disabilities. These benefits encompass business, social and emergency communications, which increase the value of the wireless network for everyone. Approximately 500 million people worldwide and 30 million people in the United States suffer from hearing loss.

Compatibility Tests Involved:

The standard calls for wireless communications devices to be measured for:

- RF Electric-field emissions
- RF Magnetic-field emissions
- T-coil mode, magnetic-signal strength in the audio band
- T-coil mode, magnetic-signal frequency response through the audio band
- T-coil mode, magnetic-signal and noise articulation index

The hearing aid must be measured for:

- RF immunity in microphone mode
- RF immunity in T-coil mode

In the following tests and results, this report includes the evaluation for a wireless communications device.

Figure 1-1 Hearing Aid *in-vitu*

[1] FCC Rule & Order, WT Docket 01-309 RM-8658

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2. TEST SITE LOCATION

I. Introduction

The map at the right shows the location of the PCTEST LABORATORY in Columbia, Maryland. It is in proximity to the FCC Laboratory, the Baltimore-Washington International (BWI) airport, the city of Baltimore and Washington, DC (See Figure 2-1).

These measurement tests were conducted at the PCTEST Engineering Laboratory, Inc. facility in New Concept Business Park, Guilford Industrial Park, Columbia, Maryland. The site address is 6660-B Dobbin Road, Columbia, MD 21045. The test site is one of the highest points in the Columbia area with an elevation of 390 feet above mean sea level. The site coordinates are 39° 11'15" N latitude and 76° 49' 38" W longitude. The facility is 1.5 miles north of the FCC laboratory, and the ambient signal and ambient signal strength are approximately equal to those of the FCC laboratory. There are no FM or TV transmitters within 15 miles of the site. The detailed description of the measurement facility was found to be in compliance with the requirements of § 2.948 according to ANSI C63.4-2003 on January 27, 2006 and Industry Canada.

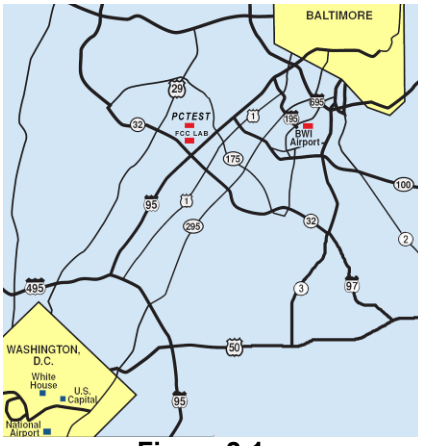

Figure 2-1
Map of the Greater Baltimore and Metropolitan Washington, D.C. Area

II. Test Facility / Accreditations:

Measurements were performed at an independent accredited PCTEST Engineering Lab located in Columbia, MD 21045, U.S.A.

- PCTEST Lab is accredited to ISO 17025-2005 by the American Association for Laboratory Accreditation (A2LA) in Specific Absorption Rate (SAR) testing, Hearing-Aid Compatibility (HAC), CTIA Test Plans, and wireless testing for FCC and Industry Canada Rules.
- PCTEST Lab is accredited to ISO 17025 by U.S. National Institute of Standards and Technology (NIST) under the National Voluntary Laboratory Accreditation Program (NVLAP Lab code: 100431-0) in EMC, FCC and Telecommunications.
- PCTEST facility is an FCC registered (PCTEST Reg. No. 90864) test facility with the site description report on file and has met all the requirements specified in Section 2.948 of the FCC Rules and Industry Canada (IC-2451).
- PCTEST Lab is a recognized U.S. Conformity Assessment Body (CAB) in EMC and R&TTE (n.b. 0982) under the U.S.-EU Mutual Recognition Agreement (MRA).
- PCTEST TCB is a Telecommunication Certification Body (TCB) accredited to ISO/IEC Guide 65 by the American National Standards Institute (ANSI) in all scopes of FCC Rules and all Industry Canada Standards (RSS).
- PCTEST facility is an IC registered (IC-2451) test laboratory with the site description on file at Industry Canada.
- PCTEST is a CTIA Authorized Test Laboratory (CATL) for AMPS and CDMA, and EvDO mobile phones.
- PCTEST is a CTIA Authorized Test Laboratory (CATL) for Over-the-Air (OTA) Antenna Performance testing for AMPS, CDMA, GSM, GPRS, EGPRS, UMTS (W-CDMA), CDMA 1xEVDO Data, CDMA 1xRTT Data.

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3. EUT DESCRIPTION

FCC ID:	A3LSPHL700
Applicant:	Samsung Electronics, Co. Ltd. 18600 Broadwick St. Rancho Dominguez, CA 90220 United States
Model(s):	SPH-L700
Serial Number:	HAC T
Tx Frequencies:	817.90 - 823.10 MHz (Cellular CDMA, Part 90S) 824.70 - 848.31 MHz (Cellular CDMA, Part 22H) 1851.25 - 1908.75 MHz (PCS CDMA, Part 24E)
HW Version:	N/A
SW Version:	L700.04 V.FA03
Maximum Conducted Power (HAC):	24.96 dBm (Cell. CDMA), 24.98 dBm (PCS CDMA)
Antenna:	Internal Antenna
HAC Test Configurations:	Cell. CDMA, 564, 1013, 384, 777, BT Off, WLAN Off, LTE Off PCS CDMA, 25, 600, 1175, BT Off, WLAN Off, LTE Off
EUT Type:	Portable Handset

Air-Interface	Band (MHz)	Type	C63.19/tested	Simultaneous Transmissions (Not to be tested)	Reduced power 20.19 (c)(1)	Voice Over Digital Transport (Data)
CDMA	850	Voice	Yes	Yes: LTE, BT or WIFI	N/A	N/A
	1900				N/A	N/A
	EVDO	Data	N/A		N/A	Yes
LTE (Band 25)	1900	Data	N/A	Yes: CDMA, BT or WIFI	N/A	Yes
BT	2450	Data	N/A	Yes: CDMA or LTE	N/A	N/A
WIFI	2450	Data	N/A	Yes: CDMA or LTE	N/A	Yes
	5200					
	5300					
	5500					
	5800					
NOTE: HAC Rating was not based on concurrent voice and data modes. Non current mode was found to represent worst case rating for both M and T rating.						

Table 3: A3LSPHL700 Air Interfaces

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4. ANSI C63.19-2007 PERFORMANCE CATEGORIES

I. RF EMISSIONS

The ANSI Standard presents performance requirements for acceptable interoperability of hearing aids with wireless communications devices. When these parameters are met, a hearing aid operates acceptably in close proximity to a wireless communications device.

Category	Telephone RF Parameters	
Near field Category	**E-field emissions CW dB(V/m)**	**H-field emissions CW dB(A/m)**
f < 960 MHz		
M1	56 to 61 + 0.5 x AWF	5.6 to 10.6 +0.5 x AWF
M2	51 to 56 + 0.5 x AWF	0.6 to 5.6 +0.5 x AWF
M3	46 to 51 + 0.5 x AWF	–4.4 to 0.6 +0.5 x AWF
M4	< 46 + 0.5 x AWF	< –4.4 + 0.5 x AWF
f > 960 MHz		
M1	46 to 51 + 0.5 x AWF	–4.4 to 0.6 +0.5 x AWF
M2	41 to 46 + 0.5 x AWF	–9.4 to –4.4 +0.5 x AWF
M3	36 to 41 + 0.5 x AWF	–14.4 to –9.4 +0.5 x AWF
M4	< 36 + 0.5 x AWF	< –14.4 + 0.5 x AWF

Table 4-1
Hearing aid and WD near-field categories as defined in ANSI C63.19-2007 [2]

II. ARTICULATION WEIGHTING FACTOR (AWF)

Standard	Technology	Articulation Weighing Factor (AWF)
T1/T1P1/3GPP	**UMTS (WCDMA)**	0
TIA/EIA/IS-2000	**CDMA**	0
iDEN™	**TDMA (22 and 11 Hz)**	0
J-STD-007	**GSM (217 Hz)**	-5

Table 4-2
Articulation Weighting Factors

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III. MAGNETIC COUPLING

Axial and Radial Field Intensity

All orientations of the magnetic field, in the axial, horizontal and vertical position along the measurement plane shall be ≥ -18 dB(A/m) at 1 kHz in a 1/3 octave band filter per 7.3.1.

Frequency Response

The frequency response of the axial component of the magnetic field shall follow the response curve specified in EIA RS-504-1983, over the frequency range 300 Hz – 3000 Hz per 7.3.2.

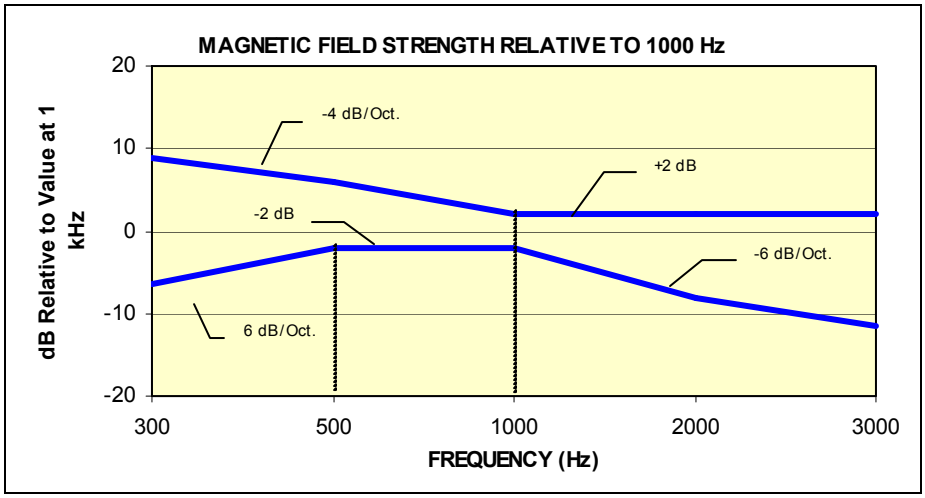

Figure 4-1
Magnetic field frequency response for Wireless Devices with an axial field ≤ -15 dB (A/m) at 1 kHz

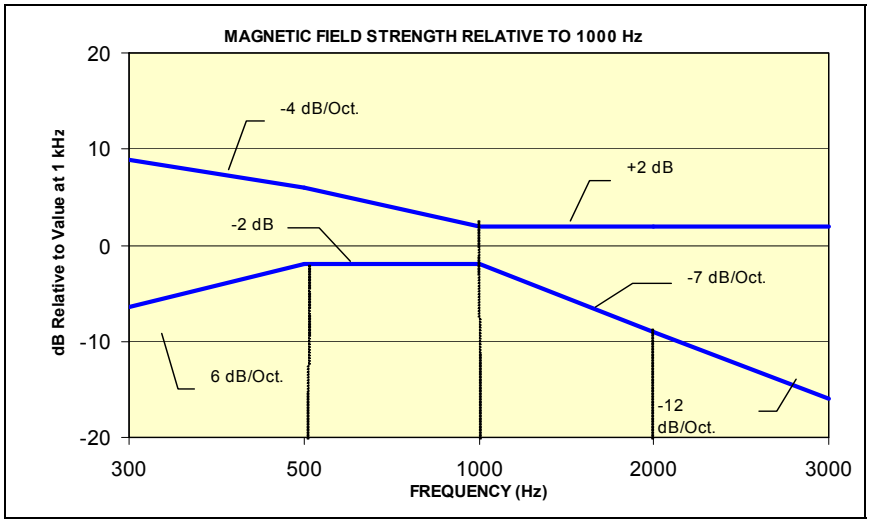

Figure 4-2
Magnetic Field frequency response for wireless devices with an axial field that exceeds -15 dB(A/m) at 1 kHz

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Signal Quality

The table below provides the signal quality requirement for the intended audio magnetic signal from a wireless device. Only the RF immunity of the hearing aid is measured in T-coil mode. It is assumed that a hearing aid can have no immunity to an interference signal in the audio band, which is the intended reception band for this mode. The only criterion that can be measured is the RF immunity in T-coil mode. This is measured using the same procedure as the audio coupling mode at the same levels.

The signal quality of the axial and radial components of the magnetic field was used to determine the T-coil mode category.

Category	Telephone RF Parameters
	Wireless Device Signal Quality (Signal + Noise-to-noise ratio in dB)
T1	0 to 10 dB
T2	10 to 20 dB
T3	20 to 30 dB
T4	> 30 dB

Table 4-3
Magnetic Coupling Parameters

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5. METHOD OF MEASUREMENT

I. Test Setup

The equipment was connected as shown in an acoustic/RF hemi-anechoic chamber:

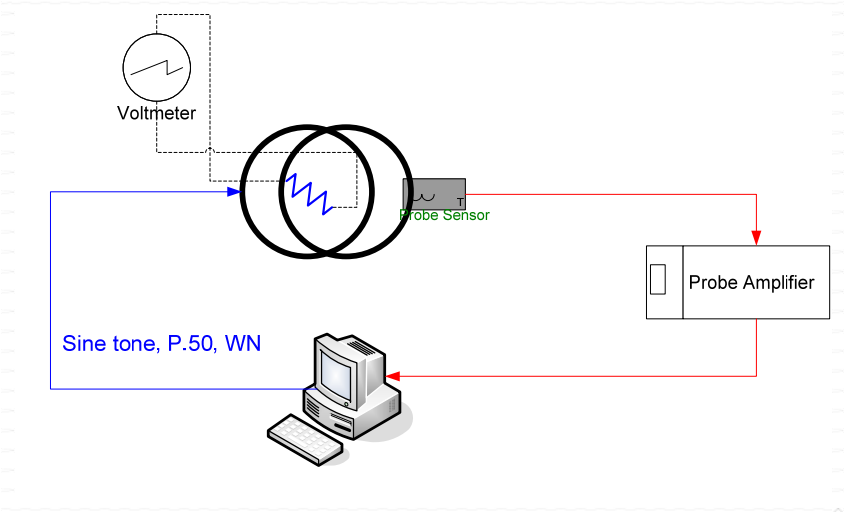

Figure 5-1 Validation Setup with Helmholtz Coil

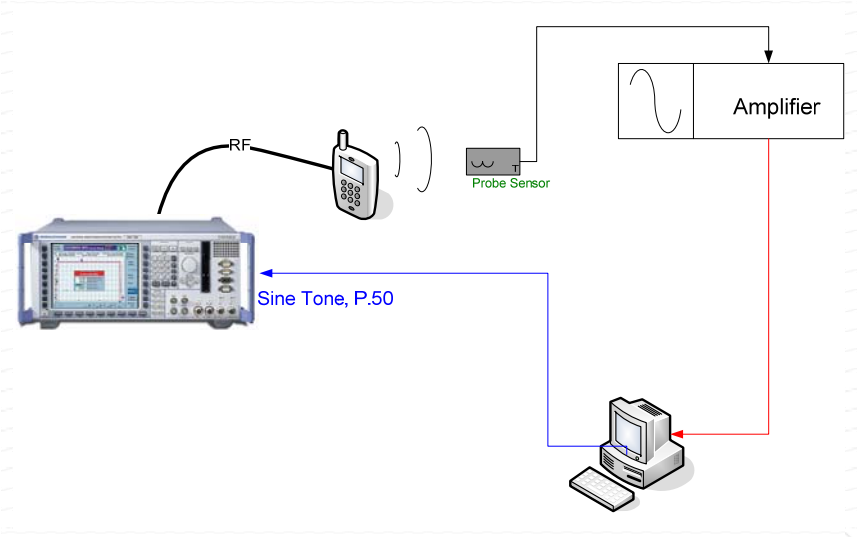

Figure 5-2 T-Coil Test Setup

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II. Scanning Mechanism

Manufacturer:	TEM
Accuracy:	± 0.83 cm/meter
Minimum Step Size:	0.1 mm
Maximum speed	6.1 cm/sec
Line Voltage:	115 VAC
Line Frequency:	60 Hz
Material Composite:	Delrin (Acetal)
Data Control:	Parallel Port
Dynamic Range (X-Y-Z):	45 x 31.75 x 47 cm
Dimensions:	36” x 25” x 38”
Operating Area:	36” x 49” x 55”
Reflections:	< -20 dB (in anechoic chamber)

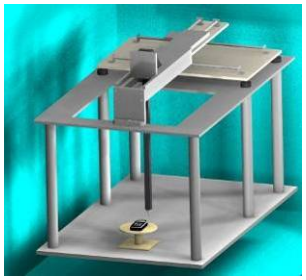

Figure 5-3
RF Near-Field Scanner

III. ITU-T P.50 Artificial Voice

Manufacturer:	ITU-T
Active Frequency Range:	100 Hz – 8 kHz
Stimulus Type:	Male and Female, no spaces
Single Sample Duration:	20.96 seconds
Activity Level:	100%

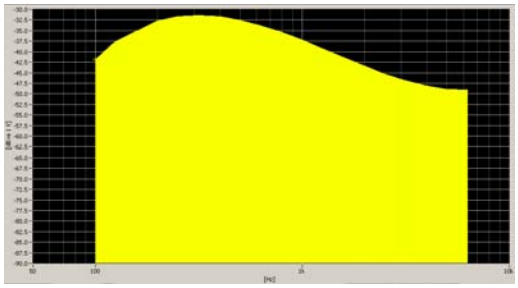

Figure 5-4
Spectral Characteristic of full P.50

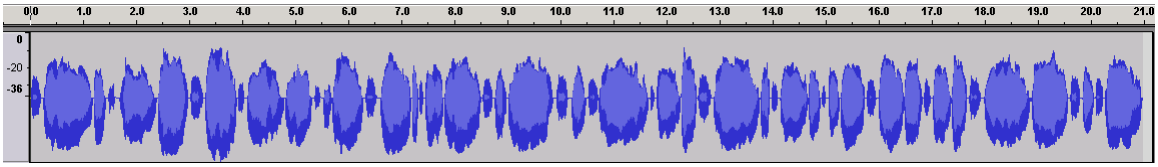

Figure 5-5
Temporal Characteristic of full P.50

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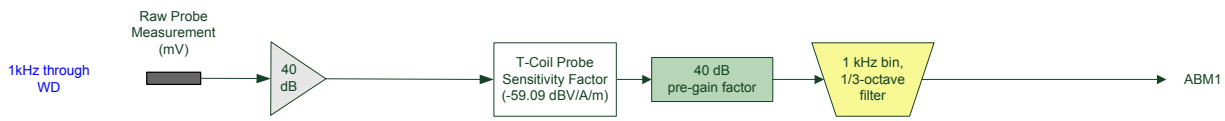
ABM1 Measurement Block Diagram:



ABM2 Measurement Block Diagram:

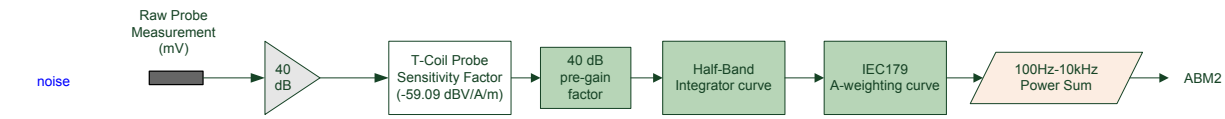


Figure 5-6 Magnetic Measurement Processing Steps

IV. Test Procedure

1. Ambient Noise Check per C63.19 §6.2.1
   a. Ambient interference was monitored using a Real-Time Analyzer between 100-10,000 Hz with 1/3 octave filtering.
   b. "A-weighting" and Half-Band Integration was applied to the measurements.
   c. Since this measurement was measured in the same method as ABM2 measurements, this level was verified to be less than 10 dB below the lowest measurement signal (which is the highest ABM2 measurement for a T4 WD). Therefore the maximum noise level for a T4 WD with an ABM1 = -18 dBA/m is:

      -18 - 30 - 10 = -58 dBA/m

2. Measurement System Validation (See Figure 5-1)
   a. The measurement system including the probe, pre-amplifier and acquisition system were validated as an entire system to ensure the reliability of test measurements.

   b. ABM1 Validation
      The magnetic field at the center of the Helmholtz coil is given by the equation (per C63.19 Annex D.9.1):

$$H_c = \frac{NI}{r\sqrt{1.25^3}} = \frac{N(\frac{V}{R})}{r\sqrt{1.25^3}}$$

Where H_c = magnetic field strength in amperes per meter
N = number of turns per coil

For the Helmholtz Coil, N=20; r=0.08m; R=10.193Ω and using V=57mV:

$$H_c = \frac{20 \cdot (\frac{0.057}{10.193})}{0.08 \cdot \sqrt{1.25^3}} = 1.0003 A/m$$

Therefore a pure tone of 1kHz was applied into the coils such that 57 mV was observed across the 10 Ω resistor. The voltmeter used for measurement was verified to be capable of measurements in the audio band range. This theoretically generates an expected field of 1 A/m in the center of the Helmholtz coil which was used to validate the probe

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measurement at 1 A/m. This was verified to be within ± 0.5 dB of the 1 A/m value (see Page 20).

c. Frequency Response Validation

The frequency response through the Helmholtz Coil was verified to be within 0.5 dB relative to 1 kHz, between 300 – 3000 Hz using the ITU-P.50 artificial speech signal as shown below:

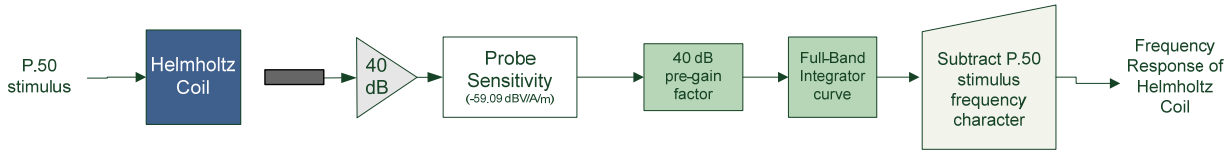

Figure 5-7 Frequency Response Validation

d. ABM2 Measurement Validation

WD noise measurements are filtered with A-weighting and Half-Band Integration over a frequency range of 100Hz – 10kHz to process ABM2 measurements. Below is the verification of the system processing A-weighting and Half-Band integration between system input to output within 0.5 dB of the theoretical result:

Table 5-1
ABM2 Frequency Response Validation

f (Hz)	HBI, A - Measured (dB re 1kHz)	HBI, A - Theoretical (dB re 1kHz)	dB Var.
100	-16.180	-16.170	-0.010
125	-13.257	-13.250	-0.007
160	-10.347	-10.340	-0.007
200	-8.017	-8.010	-0.007
250	-5.925	-5.920	-0.005
315	-4.045	-4.040	-0.005
400	-2.405	-2.400	-0.005
500	-1.212	-1.210	-0.002
630	-0.349	-0.350	0.001
800	0.071	0.070	0.001
1000	0.000	0.000	0.000
1250	-0.503	-0.500	-0.003
1600	-1.513	-1.510	-0.003
2000	-2.778	-2.780	0.002
2500	-4.316	-4.320	0.004
3150	-6.166	-6.170	0.004
4000	-8.322	-8.330	0.008
5000	-10.573	-10.590	0.017
6300	-13.178	-13.200	0.022
8000	-16.241	-16.270	0.029
10000	-19.495	-19.520	0.025

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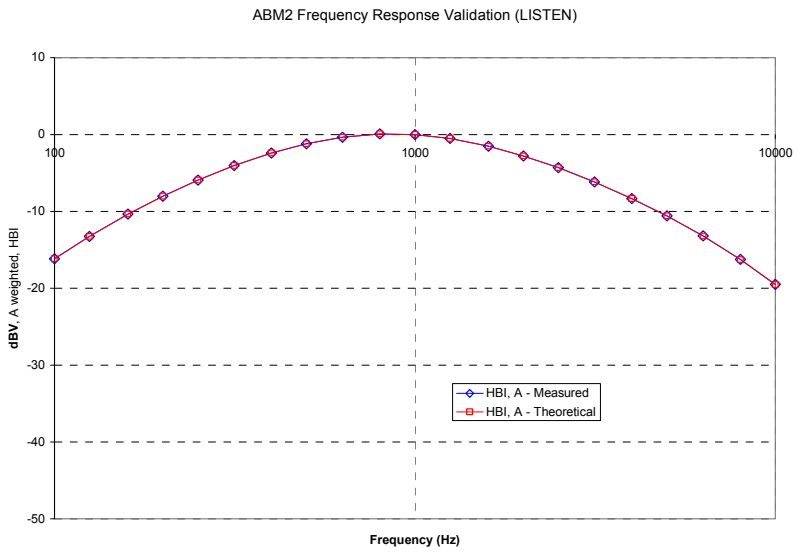

Figure 5-8
ABM2 Frequency Response Validation

The ABM2 result is a power sum from 100 Hz to 10 kHz with half-band integration and A-weighting. To verify the power sum measurement, a power sum over the full band was measured and verified to track with the source level (See Figure 5-9). Therefore the setup in this step was used to verify the power sum post-processing for ABM2 measurements. See below block diagram:

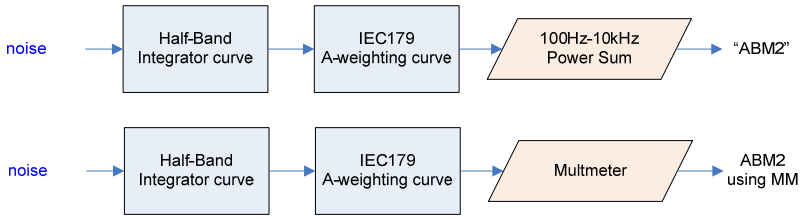

Figure 5-9
ABM2 Validation Block Diagram

The power summed output results for a known input were compared to the multi-meter results to verify any deviation in the post-processing implemented with the power-sum.

Table 5-2
ABM2 Power Sum Validation

WN Input (dBV)	Power Sum (dBV)	Multimeter-Full (dBV)	Dev (dB)
-60	-60.36	-60.2	0.16
-50	-50.19	-50.13	0.06
-40	-40.14	-40.03	0.11
-30	-30.13	-30.01	0.12
-20	-20.12	-20	0.12
-10	-10.14	-10	0.14

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Figure 5-10
ABM2 Power Sum Validation

3. Measurement Test Setup
   a. Fine scan above the WD (TEM)
      i. A multitone signal was applied to the handset such that the phone acoustic output was stable within 1dB over the probe settling time and with the acoustic output level at the C63.19 specified levels (below). The measurement step size was in 2 mm increments at a distance of 10 mm between the surface of the wireless device as shown below:

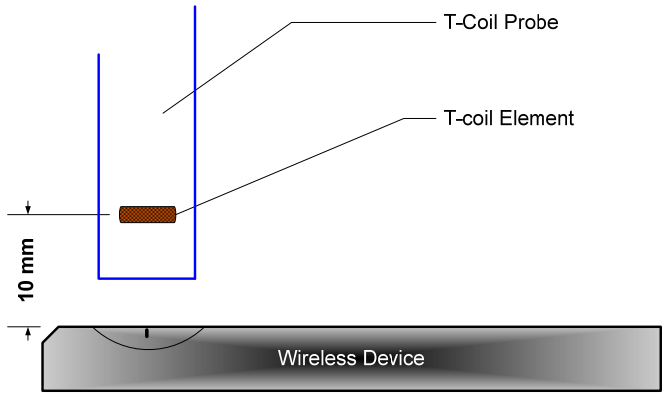

Figure 5-11
Measurement Distance

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      ii. After scanning, the planar field maximum point was determined. The position of the probe was moved to this location to setup the test using the sound check system.
      iii. These steps were repeated for the other T-coil orientations (of axial, radial transverse, or radial longitudinal) per Figure 5-16 after a T-coil orientation was fully measured with the sound check system.

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b. Speech Signal Setup to Base Station Simulator

i. C63.19 Table 6-1 states audio reference input levels for various technologies:

Standard	Technology	Input Level (dBm0)
TIA/EIA/IS-2000	CDMA	-18
J-STD-007	GSM (217 Hz)	-16
T1/T1P1/3GPP	UMTS (WCDMA)	-16
iDEN™	TDMA (22 and 11 Hz)	-18

The CMU200 audio levels were determined using base station simulator manufacturer calibration procedures resulting in the below corresponding voltages relative to handset test point level (in dBm0):

Table 5-3
CMU200 Voltage Input Levels for Audio

dBm0 Ref.	Input Voltage		Notes
3.14 dBm0	1052.0 mV	0.4 dBV	From CDMA2K "DECODER CAL". (What is needed through Encoder for FS)
-18 dBm0	92.260 mV	-20.7 dBV	For 8k Enhanced (Low)

c. Real-Time Analyzer (RTA)

i. The Real-Time Analyzer was configured to analyze measurements using 1/3 Octave band weighted filtering.

d. WD Radio Configuration Selection

i. The device was chosen to be tested in the worst-case ABM2 condition under RC1/SO3 (EVRC) (see below):

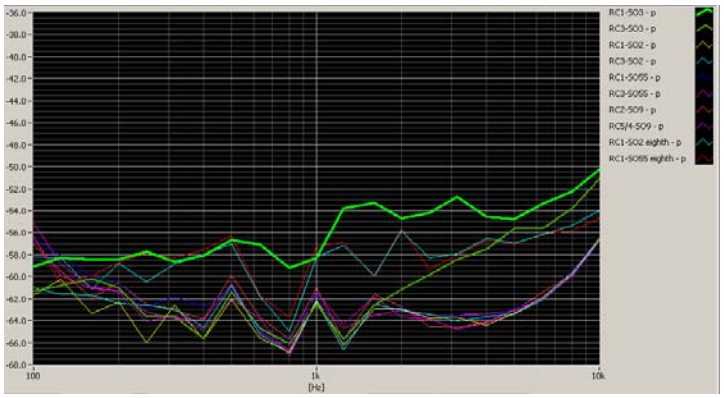

Figure 5-12
Vocoder Analysis for ABM Noise

4. Signal Quality Data Analysis

a. Narrow-band Magnetic Intensity

i. The standard specifies a 1 kHz 1/3 octave band minimum field intensity for a sine tone. The ABM1 measurements were evaluated at 1kHz with 1/3 octave band filtering over an averaged period of 10 seconds.

b. Frequency Response

i. The appropriate frequency response curve was measured to curves in Figure 4-1 or Figure 4-2 between 300 – 3000 Hz using digital linear averaging (limit lines

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chosen according to measurement found in step 4a.) A linear average over 3x the length of the artificial voice signal (3x sampling) was performed. A 10 second delay was configured in the measurement process of the stimulus to ensure handset vocoder latency effects and echo cancellation devices (if any) were appropriately stabilized during measurements.

ii. The appropriate post-processing was applied according to the system processing chain illustrated in Figure 5-13. All R10 frequencies were plotted with respect to 0dB at 1 kHz value and aligned with respect to the EIA-504 mask.

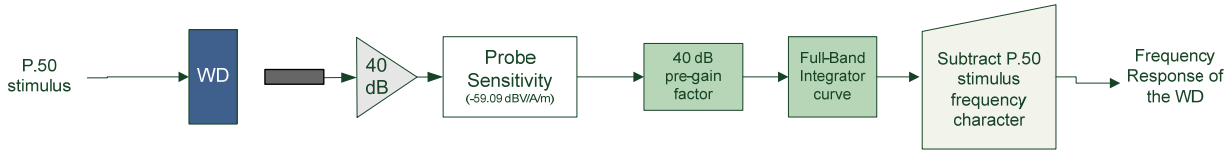

Figure 5-13 Frequency Response Block Diagram

iii. The margin is represented by the closest measured data point on the curve to the EIA-504 limit lines, in dB.

c. Signal Quality Index

i. Ensuring the WD was at maximum RF power, maximum volume, backlight on, display on, maximum contrast setting, keypad lights on (when possible) with no audio signal through the vocoder, the WD was measured over at least 100 Hz – 10,000 Hz, maximized over 5 seconds with a 50ms sample time for the ABM2 measurement (5 second time period is used in noise measurements under standards such as IEEE 269, etc.)

ii. After applying half-band integration and A-weighting to the result, a power sum was applied over each 1/3 octave bandwidth frequency for an ABM2 value

iii. This result was subtracted from the ABM1 result in step a, to obtain the Signal Quality.

V. Test Setup

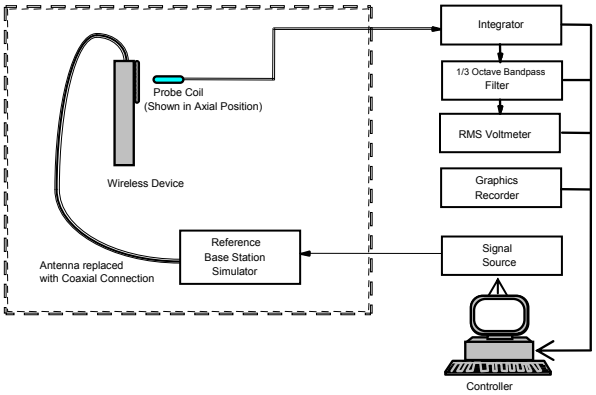

Figure 5-14
Audio Magnetic Field Test Setup

VI. Deviation from C63.19 Test Procedure

Non-conducted RF connection.

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VII. Wireless Device Channels and Frequencies

The frequencies listed in the table below are those that lie in the center of the bands used for cellular telephony. Low, middle and high channels were tested in each band for FCC compliance evaluation to ensure the maximum emission is captured across the entire band.

To facilitate setting of a base station simulator for ABM measurements, specific band plan channel numbers are listed that may be used in lieu of the band center frequencies.

Table 5-4
Center Channels and Frequencies

Test frequencies & associated channels	
Channel	**Frequency (MHz)**
Cellular 850	
384 (CDMA)	836.52
4183(UMTS)	836.60
190 (GSM)	836.60
PCS 1900	
661 (GSM)	1880
600 (CDMA)	1880
9400 (UMTS)	1880
AWS 1750	
450 (CDMA)	1732.50
1412 (UMTS)	1730.40

VIII. RF Emission Effect on T-coil Measurements

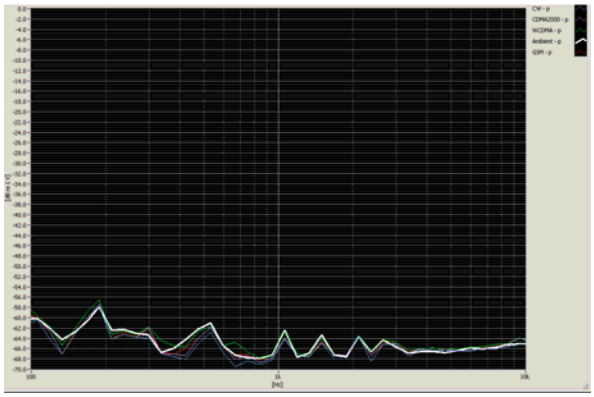

Figure 5-15
High power RF Emissions Effect with HAC Dipole on the T-coil Probe System 10mm between dipole maximum and magnetic probe

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IX. Test Flow

The flow diagram below was followed (From C63.19):

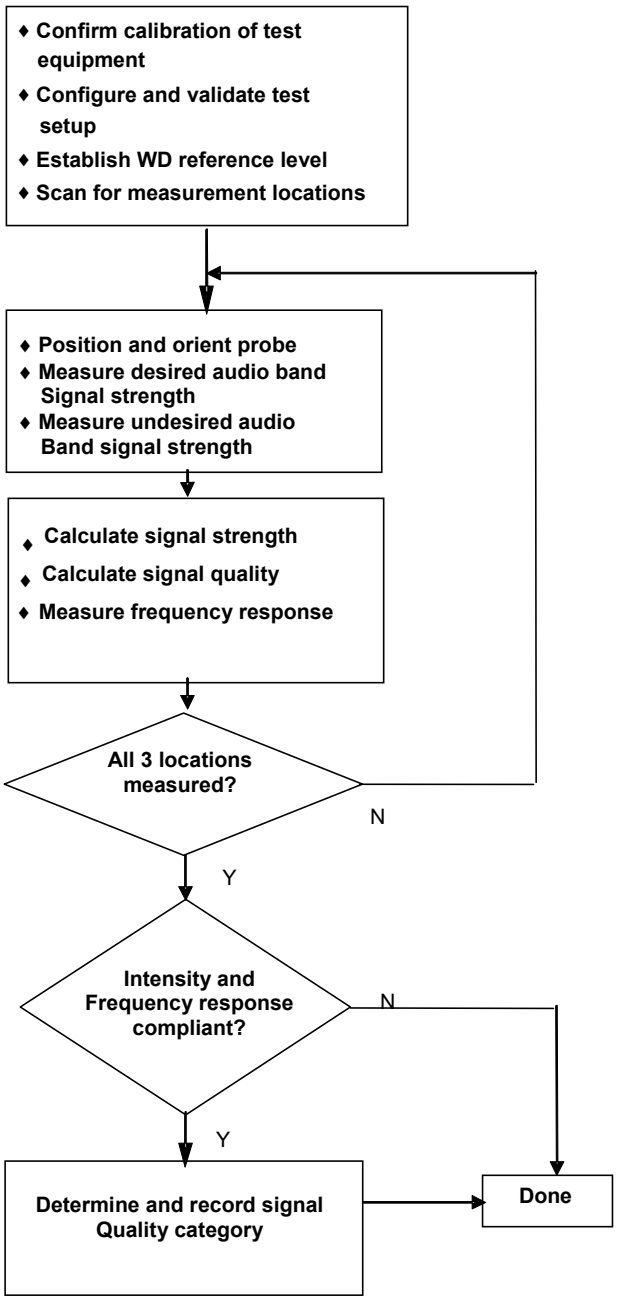

Figure 5-16
C63.19 T-Coil Signal Test Process

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6. TEST SUMMARY

I. T-Coil Test Summary

Table 6-1
Table of Results

C63.19 Sec.	Mode	Band	Test Description	Minimum Limit*	Measured	Verdict
				dBA/m	*dBA/m*	*PASS/FAIL*
7.3.1.1	CDMA	Cellular	Intensity, Axial	-18	0.5	PASS
7.3.1.2			Intensity, RadialH	-18	-8.7	PASS
7.3.1.2			Intensity, RadialV	-18	-8.3	PASS
7.3.3			Signal-to-Noise/Noise, Axial	20	38.5	PASS
7.3.3			Signal-to-Noise/Noise, RadialH	20	28.1	PASS
7.3.3			Signal-to-Noise/Noise, RadialV	20	25.7	PASS
7.3.2			Frequency Response, Axial	0	0.1	PASS
7.3.1.1	CDMA	PCS	Intensity, Axial	-18	0.5	PASS
7.3.1.2			Intensity, RadialH	-18	-8.7	PASS
7.3.1.2			Intensity, RadialV	-18	-8.2	PASS
7.3.3			Signal-to-Noise/Noise, Axial	20	35.7	PASS
7.3.3			Signal-to-Noise/Noise, RadialH	20	25.2	PASS
7.3.3			Signal-to-Noise/Noise, RadialV	20	23.0	PASS
7.3.2			Frequency Response, Axial	0	0.1	PASS

Note: The above summary table represents the worst-case numerical values according to configurations in Table 6-3.

Table 6-2
Consolidated Tabled Results

	Volume Setting	Cellular			PCS		
		Axial	RadialH	RadialV	Axial	RadialH	RadialV
Freq. Response Margin	Maximum	PASS	PASS	PASS	PASS	PASS	PASS
Magnetic Intensity Verdict		PASS	PASS	PASS	PASS	PASS	PASS
FCC SNR Verdict		PASS	PASS	PASS	PASS	PASS	PASS

Note: The above table represents the pass/fail verdict according to data in Table 6-3.

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II. Raw Handset Data

Table 6-3
Raw Data Results

	Volume	Cellular Band									
		Axial			RadialH			RadialV			
		1013	384	777	1013	384	777	1013	384	777	564
ABM1, dBA/m	Maximum	0.83	0.71	0.49	-8.28	-8.68	-8.29	-7.90	-8.26	-7.99	-8.29
ABM2, dBA/m		-37.71	-38.36	-38.72	-36.34	-37.13	-37.50	-33.56	-34.46	-35.53	-34.34
Ambient Noise, dBA/m		-61.77	-61.77	-61.77	-60.34	-60.34	-60.34	-61.16	-61.16	-61.16	-61.16
Freq. Response Margin (dB)		0.40	0.14	0.34	0.05	0.22	0.46	0.19	0.13	0.34	0.26
S+N/N (dB)		38.54	39.08	39.20	28.06	28.45	29.21	25.66	26.19	27.55	26.05
S+N/N per orientation (dB)		38.54			28.06			25.66			

	Volume	PCS Band								
		Axial			RadialH			RadialV		
		25	600	1175	25	600	1175	25	600	1175
ABM1, dBA/m	Maximum	0.65	0.57	0.51	-8.73	-8.55	-8.69	-7.82	-8.19	-8.05
ABM2, dBA/m		-37.57	-36.22	-35.18	-37.00	-36.50	-33.87	-33.75	-33.61	-31.02
Ambient Noise, dBA/m		-61.77	-61.77	-61.77	-60.34	-60.34	-60.34	-61.16	-61.16	-61.16
Freq. Response Margin (dB)		0.17	0.17	0.06	0.42	0.39	0.17	0.28	0.22	0.14
S+N/N (dB)		38.22	36.79	35.69	28.27	27.95	25.19	25.93	25.42	22.97
S+N/N per orientation (dB)		35.69			25.19			22.97		
T-coil Coordinates (cm)	[x,y] from bottom left	2.8,2.4			2.8,3.4			3.4,2.8		

Note: ABM1 >> Ambient noise

WD Configuration

1. Radio Configuration: RC1/SO3 (EVRC)
2. Power Configuration: Power Control Bits = "All Up"
3. Phone Condition: Mute on; Backlight on; Max Volume, Max Contrast

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III. Frequency Response Graph

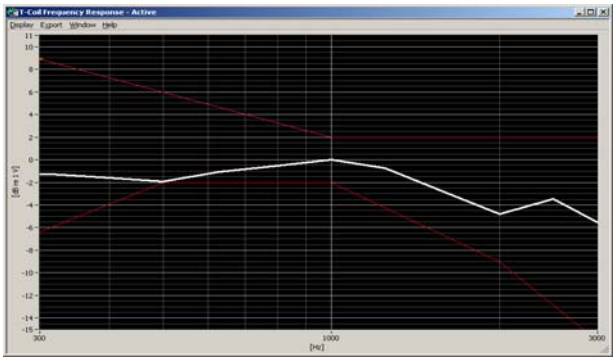
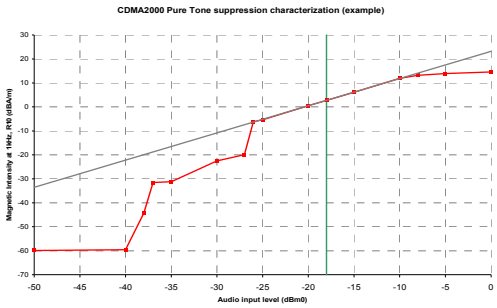


Figure 6-1
Axial Frequency Response

Note: This frequency response represents the worst-case ABM2 test configuration according to Table 6-3.

IV. 1 kHz Vocoder Application Check



This model was verified to be within the linear region for ABM1 measurements. This measurement was taken in the axial configuration above the ABM1 maximum location/configuration derived from Table 6-3.

V. Undesirable Audio Magnetic Band Plot (ABM2)

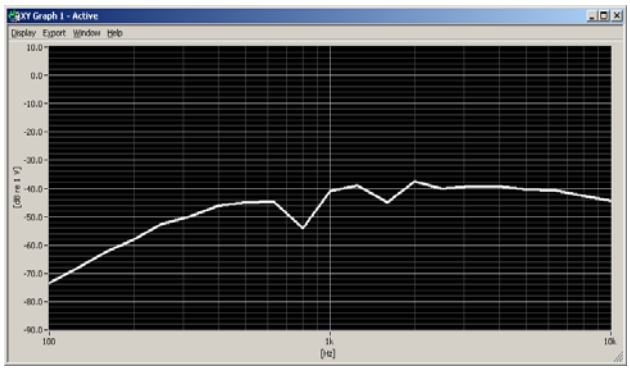


Figure 6-2
Worst-case ABM2 Plot for WD

Note: This plot represents the data from the location/configuration resulting in the highest ABM2 result shown in Table 6-3.

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VI. T-Coil Validation Test Results

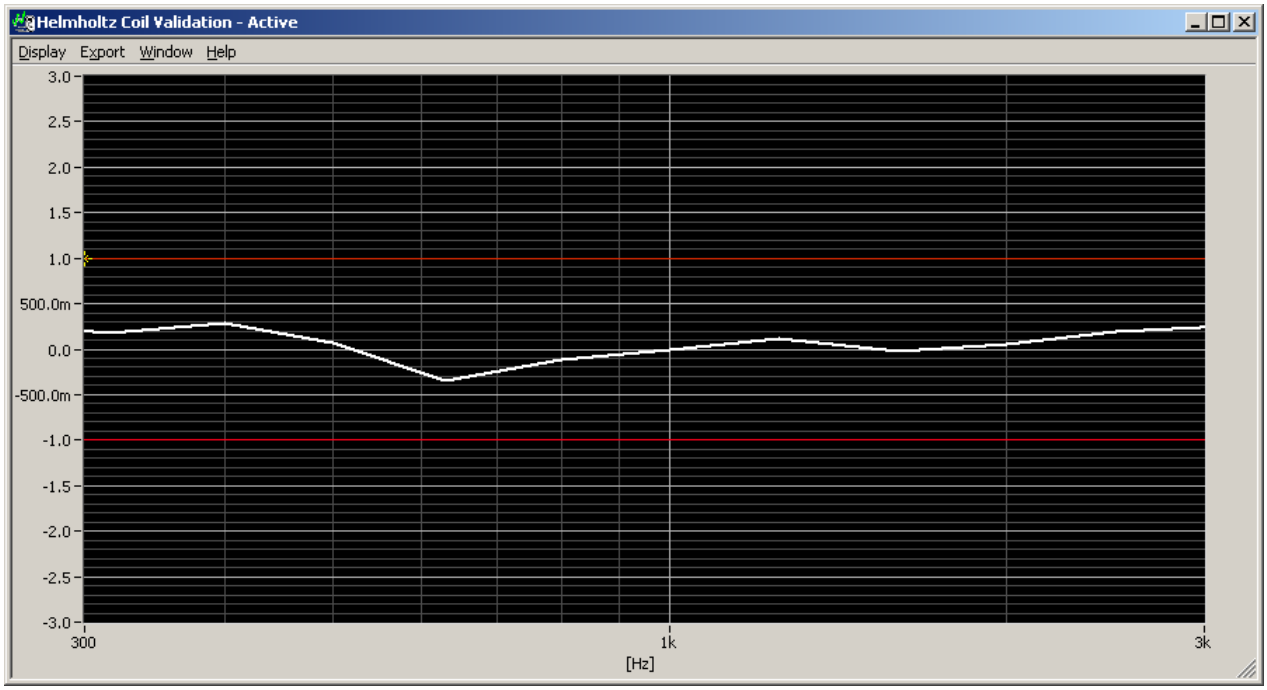

Figure 6-3
Helmholtz Coil Validation for Frequency Response

Table 6-4
Helmholtz Coil Validation Table of Results

Item	Target	Result	Verdict
Signal Validation			
Frequency Response, from limits	*0 ± 0.5 dB*	0.34	**PASS**
Magnetic Intensity, -10 dBA/m	*-10 ± 0.5 dB*	-9.874	**PASS**
Noise Validation			
Axial Environmental Noise	< - 58 dBA/m	-61.77	**PASS**
RadialH Environmental Noise	< - 58 dBA/m	-60.34	**PASS**
RadialV Environmental Noise	< - 58 dBA/m	-61.16	**PASS**

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7. FCC 3G MEASUREMENTS

Radio Configuration 1, Service Option 3 (thick, green data curve) was used for the testing as the worst-case configuration for the handset due to vocoder gating from the EVRC logic. See below plot for ABM noise comparison between operational field service options and radio configurations for a CDMA2000 handset:

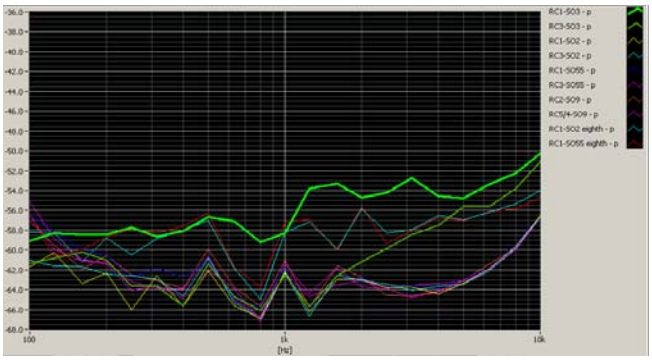

Figure 7-1
CDMA2000 Audio Band Magnetic Noise

I. ABM Measurements

ABM2 Pre-Test (dBA/m), A, HBI

RC1/SO3	RC3/SO3	RC4/SO3	Orientation	Channel
-31.18	-49.31	-49.2	RadialV	1175

ABM1 Pre-Test (dBA/m)

RC1/SO3	RC3/SO3	RC4/SO3	Orientation	Channel
-8.420	-8.040	-8.480	RadialV	1175

- Mute on; Backlight on; Max Volume, Max Contrast
- Power Control Bits = "All Up"

Figure 7-2
Audio Band Magnetic Curve Measurement Block Diagram

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8. MEASUREMENT UNCERTAINTY

Table 8-1
Uncertainty Estimation Table

Contribution	Data +/- %	Data +/- dB	Data Type	Probability distribution	Divisor	Standard uncertainty	Standard Uncertainty (dB)
ABM Noise	7.0%	0.29	Std. Dev.	Normal k=1	1.00	7.0%	
RF Reflections	4.7%	0.20	Specification	Rectangular	1.73	2.7%	
Reference Signal Level	12.2%	0.50	Specification	Rectangular	1.73	7.0%	
Positioning Accuracy	10.0%	0.41	Uncertainty	Rectangular	1.73	5.8%	
Probe Coil Sensitivity	12.2%	0.50	Specification	Rectangular	1.73	7.0%	
Probe Linearity	2.4%	0.10	Std. Dev.	Normal k=1	1.00	2.4%	
Cable Loss	2.8%	0.12	Specification	Rectangular	1.73	1.6%	
Frequency Analyzer	5.0%	0.21	Specification	Rectangular	1.73	2.9%	
System Repeatability	5.0%	0.21	Std. Dev.	Normal k=1	1.00	5.0%	
WD Repeatability	9.0%	0.37	Std. Dev.	Normal k=1	1.00	9.0%	
Positioner Accuracy	1.0%	0.04	Specification	Rectangular	1.73	0.6%	
Combined standard uncertainty, uc (k=1)						17.7%	0.71
Expanded uncertainty (k=2), 95% confidence level						35.3%	1.31

Notes:
1. Test equipments are calibrated according to techniques outlined in NIS81, NIS3003 and NIST Tech Note 1297.
2. All equipments have traceability according to NIST. Measurement Uncertainties are defined in further detail in NIS 81 and NIST Tech Note 1297 and UKAS M3003.

Measurement uncertainty reflects the quality and accuracy of a measured result as compared to the true value. Such statements are generally required when stating results of measurements so that it is clear to the intended audience that the results may differ when reproduced by different facilities. Measurement results vary due to the measurement uncertainty of the instrumentation, measurement technique, and test engineer. Most uncertainties are calculated using the tolerances of the instrumentation used in the measurement, the measurement setup variability, and the technique used in performing the test. While not generally included, the variability of the equipment under test also figures into the overall measurement uncertainty. Another component of the overall uncertainty is based on the variability of repeated measurements (so-called Type A uncertainty). This may mean that the Hearing Aid compatibility tests may have to be repeated by taking down the test setup and resetting it up so that there are a statistically significant number of repeat measurements to identify the measurement uncertainty. By combining the repeat measurement results with that of the instrumentation chain using the technique contained in NIS 81 and NIS 3003, the overall measurement uncertainty was estimated.

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9. EQUIPMENT LIST

Table 9-1
Equipment List

Manufacturer	Model	Description	Cal Date	Cal Interval	Cal Due	Serial Number
Agilent	E4407B	ESA Spectrum Analyzer	4/5/2011	Annual	4/5/2012	US39210313
Agilent	E5515C	Wireless Communications Tester	4/21/2011	Annual	4/21/2012	US41140256
Agilent	E5515C	Wireless Communications Test Set	10/14/2011	Annual	10/14/2012	GB43304447
Gigatronics	80701A	(0.05-18GHz) Power Sensor	10/12/2011	Annual	10/12/2012	1833460
Gigatronics	8651A	Universal Power Meter	10/12/2011	Annual	10/12/2012	8650319
Listen	Soundconnect	Microphone Power Supply	7/13/2011	Annual	7/13/2012	PS1435
Listen	SoundCheck	Acoustic Analyzer System	8/23/2011	Annual	8/23/2012	40603797
NI	4474	Data Acquisition Card	N/A		N/A	N/A
Rohde & Schwarz	CMU200	Base Station Simulator	4/19/2011	Annual	4/19/2012	107826
Rohde & Schwarz	CMU200	Base Station Simulator	6/1/2011	Annual	6/1/2012	833855/0010
Rohde & Schwarz	CMW500	LTE Radio Communication Tester	10/7/2011	Annual	10/7/2012	103962
TEM	Axial T-coil Probe	Axial T-Coil Probe	6/15/2011	Annual	6/15/2012	TEM-1105
TEM	Radial T-Coil Probe	Radial T-Coil Probe	6/15/2011	Annual	6/15/2012	TEM-1121
TEM	Radial T-Coil Probe	Radial T-Coil Probe	1/20/2012	Annual	1/20/2013	TEM-1130
TEM	Axial T-Coil Probe	Axial T-Coil Probe	1/20/2012	Annual	1/20/2013	TEM-1124
TEM	C63.19	Helmholtz Coil	11/11/2011	Biennial	11/11/2013	925
TEM		HAC System Controller with Software	N/A		N/A	N/A
TEM		HAC Positioner	N/A		N/A	N/A

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10. CALIBRATION CERTIFICATES

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West Caldwell Calibration Laboratories Inc.

Certificate of Calibration

for

Axial T Coil Probe

Manufactured by:	TEM CONSULTING
Model No:	Axial T Coil Probe
Serial No:	TEM-1124
Calibration Recall No:	21559

Submitted By:

Customer:	STEVE LIU
Company:	PCTEST ENGINEERING LAB
Address:	6660-B DOBBIN ROAD COLUMBIA MD 21045

The subject instrument was calibrated to the indicated specification using standards traceable to the National Institute of Standards and Technology or to accepted values of natural physical constants. This document certifies that the instrument met the following specification upon its return to the submitter.

West Caldwell Calibration Laboratories Procedure No. Axial T Coi TEM

Upon receipt for Calibration, the instrument was found to be:

Within (X) see attached Report of Calibration.

the tolerance of the indicated specification.

West Caldwell Calibration Laboratories' calibration control system meets the requirements, ISO 10012-1 MIL-STD-45662A, ANSI/NCSL Z540-1, IEC Guide 25, ISO 9001:2008 and ISO 17025.

Note: With this Certificate, Report of Calibration is included.

Calibration Date: 20-Jan-12 1/27/12

Certificate No: 21559 - 1

QA Doc. #1051 Rev. 2.0 10/1/01

Certificate Page 1 of 1

Approved by:

Felix Christopher
Quality Manager

West Caldwell Calibration Laboratories, Inc.
uncompromised calibration
1575 State Route 96, Victor, NY 14564, U.S.A.

ISO 9001:2008 Registered Company
Calibration Traceable To N. I. S. T.

Phone: (585) 586-3900 Fax.: (585) 586-4327

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West Caldwell Calibration Laboratories, Inc.
uncompromised calibration

1575 State Route 96, Victor NY 14564

ACCREDITATION ISO/IEC 17025
ACCREDITED
1533.01

REPORT OF CALIBRATION

for

TEM Consulting LP Axial T Coil Probe **Model No.: Axial T Coil Probe** **Serial No.: TEM-1124**

Company : Pctest Engineering Lab. **I. D. No: 80578**

Calibration results: **Before data: .....** **After data: .....**

Probe Sensitivity measured with Helmholtz Coil

Before & after data same: ...X.....

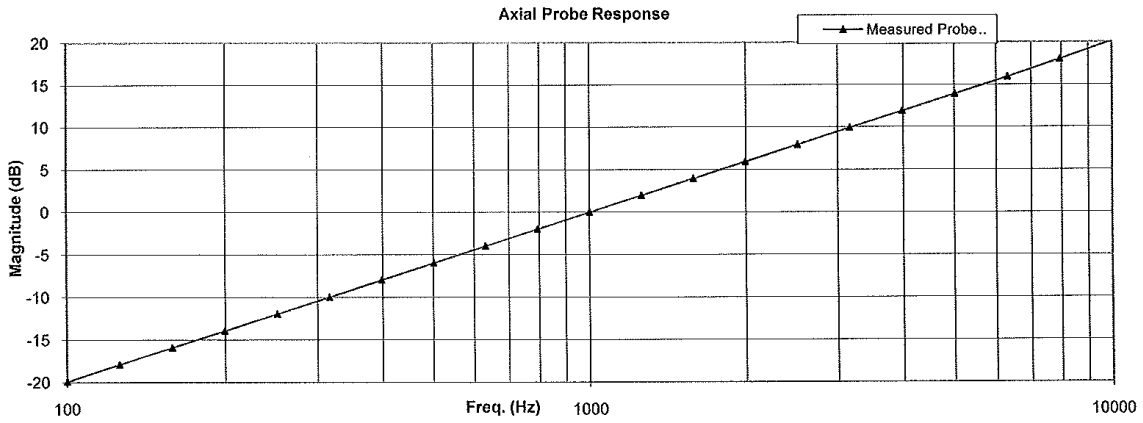
Helmholtz Coil;					
the number of turns on each coil;	10	No.			
the radius of each coil, in meters;	0.204	m	Laboratory Environment:		
the current in the coils, in amperes.;	0.08	A	Ambient Temperature:	22.1	°C
Helmholtz Coil Constant;	6.98	A/m/V	Ambient Humidity:	30.8	% RH
Helmholtz Coil magnetic field;	5.90	A/m	Ambient Pressure:	100.1	kPa
			Calibration Date:	20-Jan-12	1:01 PM
Probe Sensitivity at	1000	Hz.	Re-calibration Due:	20-Jan-13	
was	-60.16	dBV/A/m	Report Number:	21559	-1
	0.981	mV/A/m	Control Number:	21559	
Probe resistance	904	Ohms			

The above listed instrument meets or exceeds the tested manufacturer's specifications.

This Calibration is traceable through NIST test numbers: ,205342

The expanded uncertainty of calibration: 0.30dB at 95% confidence level with a coverage factor of k=2.

Graph represents Probes Frequency Response.



The above listed instrument was checked using calibration procedure documented in West Caldwell Calibration Laboratories Inc. procedure : **Rev. 5.0 Sept. 10, 2010 Doc. # 1038 HCATEMC**

Calibration was performed by West Caldwell Calibration Laboratories Inc. under Operating Procedures intended to implement the requirements of ISO10012-1, IEC Guide 25, ANSI/NCSL Z540-1, (MIL-STD-45662A) and ISO 9001:2008, ISO 17025

Cal. Date: 20-Jan-2012 1:01 PM Measurements performed by: .....

Calibrated on WCCL system type 9700 **Felix Christopher**

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HCATEMC_TEM-1124_Jan-20-2012

West Caldwell Calibration Laboratories Inc.

1575 State Route 96, Victor NY 14564
Tel. (585) 586-3900 FAX (585) 586-4327

Calibration Data Record

for

TEM Consulting LP Axial T Coil Probe — Model No.: Axial T Coil Probe — Serial No.: TEM-1124

Company : Pctest Engineering Lab.

Test	Function	Tolerance		Measured values Before	Out	Remarks
1.0	Probe Sensitivity at	1000 Hz.	dBV/A/m	-60.16		
			dB			
2.0	Probe Level Linearity		6	6.03		
		Ref. (0 dB)	0	0.00		
			-6	-6.02		
			-12	-12.03		
			Hz			
3.0	Probe Frequency Response		100	-19.9		
			126	-17.9		
			158	-15.9		
			200	-13.9		
			251	-11.9		
			316	-10.0		
			398	-8.0		
			501	-6.0		
			631	-4.0		
			794	-2.0		
		Ref. (0 dB)	1000	0.0		
			1259	2.0		
			1585	4.0		
			1995	6.0		
			2512	7.9		
			3162	9.9		
			3981	11.9		
			5012	13.9		
			6310	15.9		
			7943	18.0		
			10000	20.2		

Instruments used for calibration:			Date of Cal.	Traceablity No.	Due Date
HP	34401A	S/N US360641	17-Oct-2011	,205342	16-Oct-2012
HP	34401A	S/N US361024	17-Oct-2011	,205342	16-Oct-2012
HP	33120A	S/N S3604371	17-Oct-2011	,205342	16-Oct-2012
B&K	2133	S/N 1492410	4-Nov-2011	681/280411-11	4-Nov-2012

Cal. Date: 20-Jan-2012 1:01 PM — Tested by: Felix Christopher

Calibrated on WCCL system type 9700

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Rev. 5.0 Sept. 10, 2010 Doc. # 1038 HCATEMC

Page 2 of 2

West Caldwell Calibration Laboratories Inc.

Certificate of Calibration

for

Radial T Coil Probe

Manufactured by:	TEM CONSULTING
Model No:	Radial T Coil Probe
Serial No:	TEM-1130
Calibration Recall No:	21559

Submitted By:

Customer:	STEVE LIU
Company:	PCTEST ENGINEERING LAB
Address:	6660-B DOBBIN ROAD COLUMBIA MD 21045

The subject instrument was calibrated to the indicated specification using standards traceable to the National Institute of Standards and Technology or to accepted values of natural physical constants. This document certifies that the instrument met the following specification upon its return to the submitter.

West Caldwell Calibration Laboratories Procedure No. Radial T C TEM

Upon receipt for Calibration, the instrument was found to be:

Within (X) see attached Report of Calibration.

the tolerance of the indicated specification.

West Caldwell Calibration Laboratories' calibration control system meets the requirements, ISO 10012-1 MIL-STD-45662A, ANSI/NCSL Z540-1, IEC Guide 25, ISO 9001:2008 and ISO 17025.

Note: With this Certificate, Report of Calibration is included.

OK ✓ SP 1/27/12

Calibration Date: 20-Jan-12

Certificate No: 21559 - 2

QA Doc. #1051 Rev. 2.0 10/1/01

Certificate Page 1 of 1

Approved by:

Felix Christopher
Quality Manager

West Caldwell Calibration Laboratories, Inc.
uncompromised calibration
1575 State Route 96, Victor, NY 14564, U.S.A.

ISO 9001:2008 Registered Company
Calibration Traceable To N. I. S. T.

ACCREDITATION ISO/IEC 17025 ACCREDITED 1513.01

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1575 State Route 96, Victor NY 14564

ACCREDITATION ISO/IEC 17025
ACCREDITED
1533.01

REPORT OF CALIBRATION

for

TEM Consulting LP Radial T Coil Probe **Model No.: Radial T Coil Probe** **Serial No.: TEM-1130**

Company : Pctest Engineering Lab. **I. D. No: 80579**

Calibration results: **Before data: .....** **After data: .....**

Probe Sensitivity measured with Helmholtz Coil

Before & after data same: ...X.....

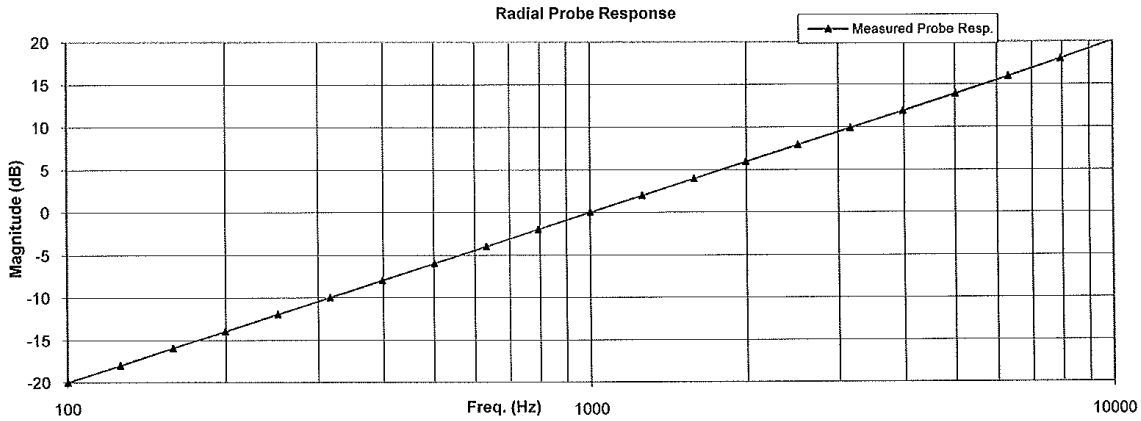
Helmholtz Coil;					
the number of turns on each coil;	10	No.			
the radius of each coil, in meters;	0.204	m	Laboratory Environment:		
the current in the coils, in amperes.;	0.08	A	Ambient Temperature:	22.1	°C
Helmholtz Coil Constant;	6.98	A/m/V	Ambient Humidity:	30.8	% RH
Helmholtz Coil magnetic field;	5.90	A/m	Ambient Pressure:	100.1	kPa
			Calibration Date:	20-Jan-12	1:30 PM
Probe Sensitivity at	1000	Hz.	Re-calibration Due:	20-Jan-13	
was	-60.50	dBV/A/m	Report Number:	21559	-2
	0.944	mV/A/m	Control Number:	21559	
Probe resistance	903	Ohms			

The above listed instrument meets or exceeds the tested manufacturer's specifications.

This Calibration is traceable through NIST test numbers: ,205342

The expanded uncertainty of calibration: 0.30dB at 95% confidence level with a coverage factor of k=2.

Graph represents Probes Frequency Response.



The above listed instrument was checked using calibration procedure documented in West Caldwell Calibration Laboratories Inc. procedure : **Rev. 5.0 Sept. 10, 2010 Doc. # 1038 HCRTEMC**

Calibration was performed by West Caldwell Calibration Laboratories Inc. under Operating Procedures intended to implement the requirements of ISO10012-1, IEC Guide 25, ANSI/NCSL Z540-1, (MIL-STD-45662A) and ISO 9001:2008, ISO 17025

Cal. Date: 20-Jan-2012 1:30 PM Measurements performed by: .....

Calibrated on WCCL system type 9700 **Felix Christopher**

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HCRTEMC_TEM-1130_Jan-20-2012

West Caldwell Calibration Laboratories Inc.

1575 State Route 96, Victor NY 14564
Tel. (585) 586-3900 FAX (585) 586-4327

Calibration Data Record

for

TEM Consulting LP Radial T Coil Probe **Model No.: Radial T Coil Probe** **Serial No.: TEM-1130**

Company : Pctest Engineering Lab.

Test	Function	Tolerance		Measured values Before	Out	Remarks
1.0	Probe Sensitivity at	1000 Hz.	dBV/A/m	-60.50		
			dB			
2.0	Probe Level Linearity		6	6.03		
		Ref. (0 dB)	0	0.00		
			-6	-6.02		
			-12	-12.02		
			Hz			
3.0	Probe Frequency Response		100	-20.0		
			126	-18.0		
			158	-15.9		
			200	-13.9		
			251	-11.9		
			316	-10.0		
			398	-8.0		
			501	-6.0		
			631	-4.0		
			794	-2.0		
		Ref. (0 dB)	1000	0.0		
			1259	2.0		
			1585	4.0		
			1995	6.0		
			2512	7.9		
			3162	9.9		
			3981	11.9		
			5012	13.9		
			6310	15.9		
			7943	18.0		
			10000	20.1		

Instruments used for calibration:			Date of Cal.	Traceability No.	Due Date
HP	34401A	S/N US360641	17-Oct-2011	,205342	16-Oct-2012
HP	34401A	S/N US361024	17-Oct-2011	,205342	16-Oct-2012
HP	33120A	S/N S3604371	17-Oct-2011	,205342	16-Oct-2012
B&K	2133	S/N 1492410	4-Nov-2011	681/280411-11	4-Nov-2012

Cal. Date: 20-Jan-2012 1:30 PM **Tested by: Felix Christopher**

Calibrated on WCCL system type 9700

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11. CONCLUSION

The measurements indicate that the wireless communications device complies with the HAC limits specified in accordance with the ANSI C63.19 Standard and FCC WT Docket No. 01-309 RM-8658. Precise laboratory measures were taken to assure repeatability of the tests. The tested device complies with the requirements in respect to all parameters specific to the test. The test results and statements relate only to the item(s) tested.

The measurement system and techniques presented in this evaluation are proposed in the ANSI standard as a means of best approximating wireless device compatibility with a hearing-aid. The literature is under continual re-construction.

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